



Argonne  
NATIONAL  
LABORATORY

*... for a brighter future*



U.S. Department  
of Energy

UChicago ►  
Argonne<sub>LLC</sub>



Office of  
Science  
U.S. DEPARTMENT OF ENERGY

A U.S. Department of Energy laboratory  
managed by UChicago Argonne, LLC

## *XAS Data Processing*

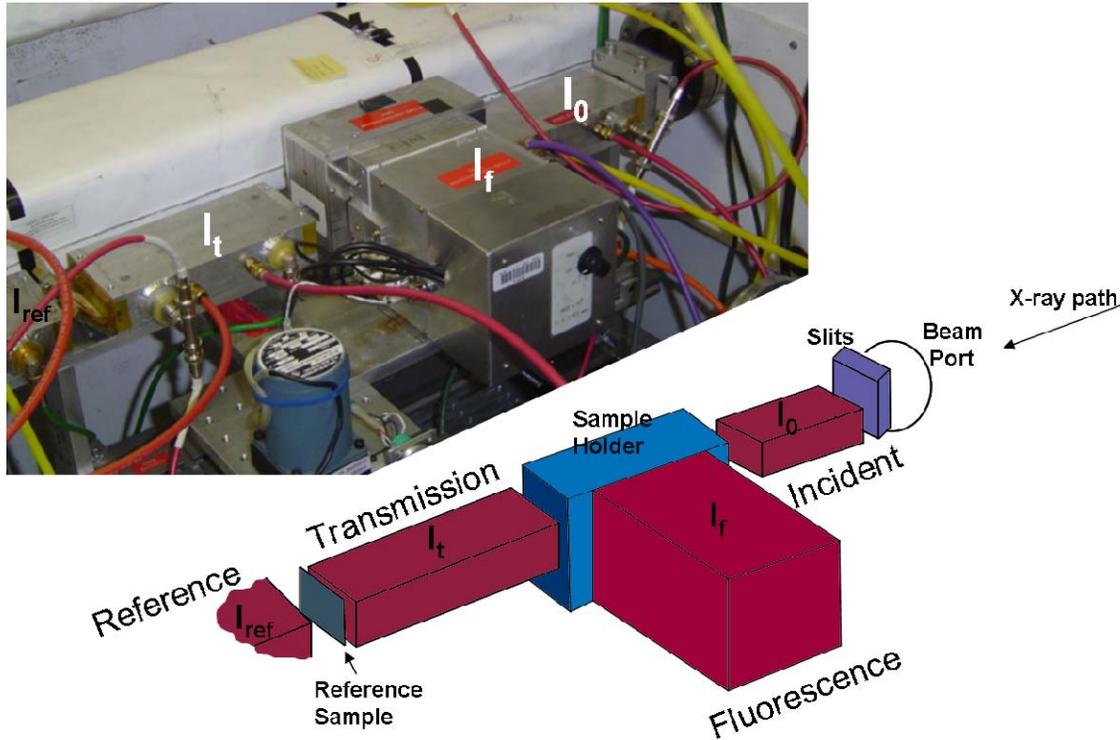
*Shelly Kelly*

*Argonne National Laboratory*

## Outline

- X-ray absorption signal
- Reference spectra
- Aligning and merging EXAFS signals
- Normalizing EXAFS spectra
- Conversion from energy to wavenumber
- Basics of Fourier transforms
- Background functions
- Fourier transform k-weights
- EXAFS Equation

# X-ray Absorption Measurement

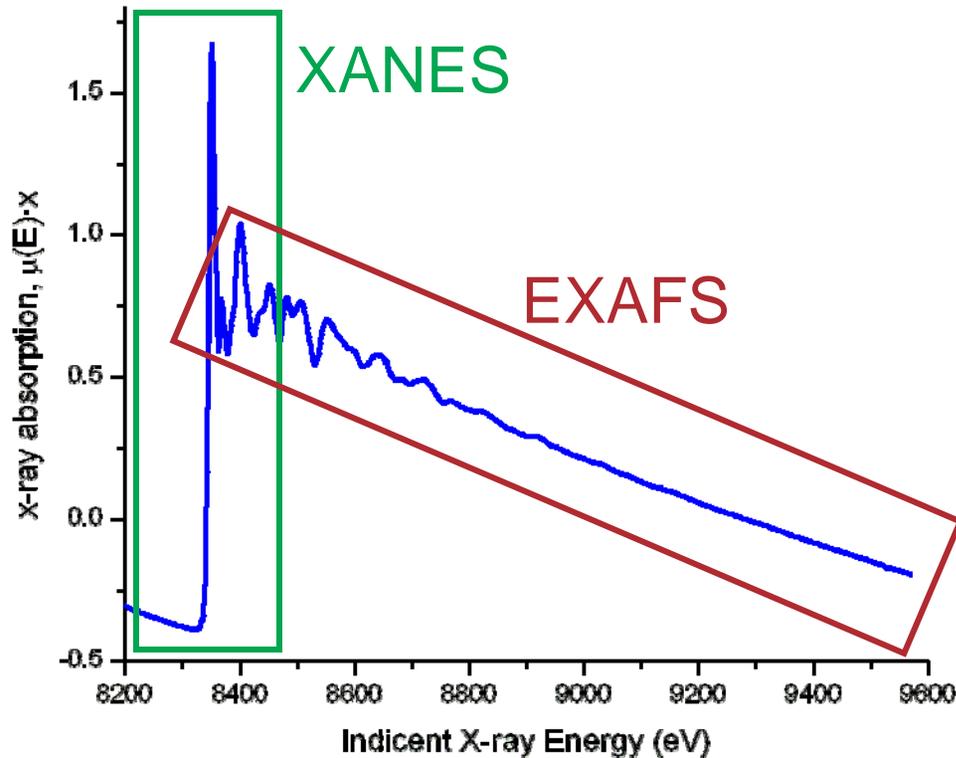


$$I_t = I_0 e^{-\mu \cdot x}$$

$$\mu \cdot x \propto \frac{I_f}{I_0}$$

The number of X-rays transmitted ( $I_t$ ) through a sample is given the intensity of X-rays impinging on the sample ( $I_0$ ) decreased exponentially by the thickness of the sample ( $x$ ) and the absorption coefficient of the sample ( $\mu$ )

## X-ray Absorption Cross Section



Transmission Signal

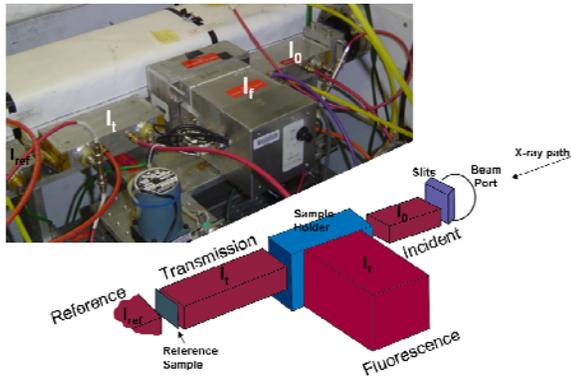
$$\mu \cdot x = \ln \left( \frac{I_0}{I_t} \right)$$

Fluorescence Signal

$$\mu \cdot x \propto \frac{I_f}{I_0}$$

- XAS: X-ray Absorption Spectroscopy
  - XANES: X-ray Absorption Near Edge Structure
  - EXAFS: Extended X-ray Absorption Fine Structure

# Reference Spectra



Reference Placed in beam behind sample

$$\mu \cdot x = \ln \left( \frac{I_t}{I_{ref}} \right)$$

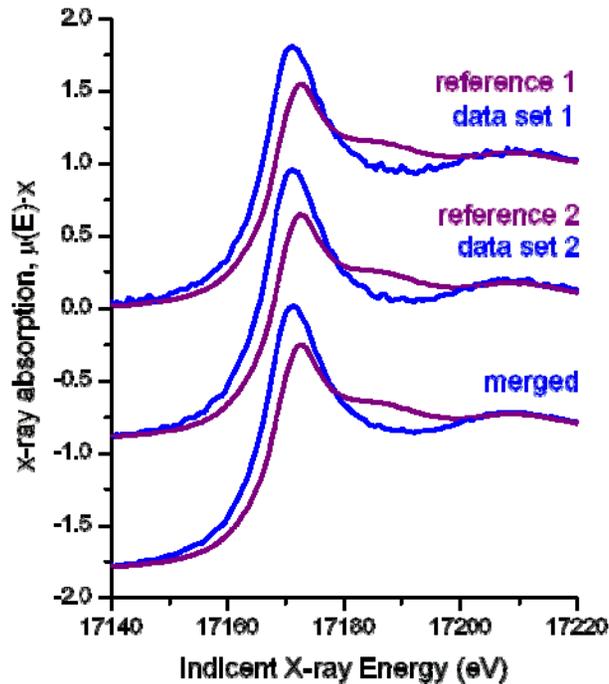
Reference placed beside beam<sup>1</sup>

$$\mu \cdot x = \ln \left( \frac{I_0}{I_{ref}} \right)$$

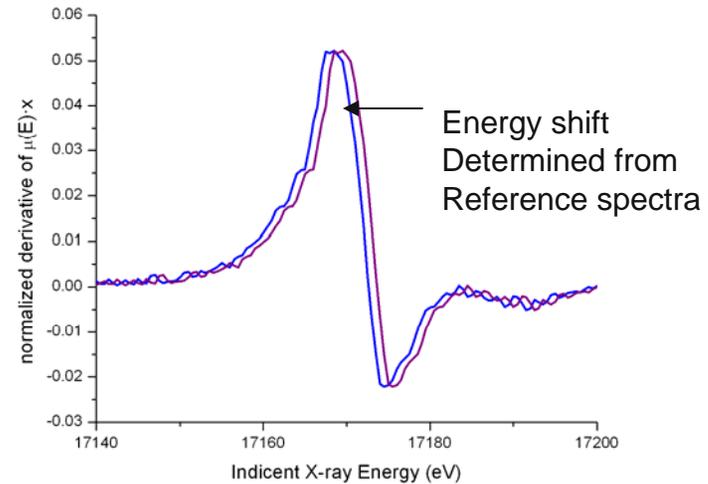
- X-ray absorption spectra should be checked for alignment before the spectra are averaged.
- A reference spectra can be collected with each sample spectra for this purpose.
  - Reference place behind transmission ionization chamber
  - Reference placed beside x-ray beam with a pin diode detector (for samples that do not transmit x-rays)
- The reference spectra are then shifted in energy so that their absorption edges are aligned and the shift is applied to the corresponding sample spectrum

<sup>1</sup>Cross J. O. and Frenkel A. I. (1998) Use of scattered radiation for absolute energy calibration. *Rev. Sci. Instrum.* **70**, 38-40.

# Aligning and Averaging Spectra

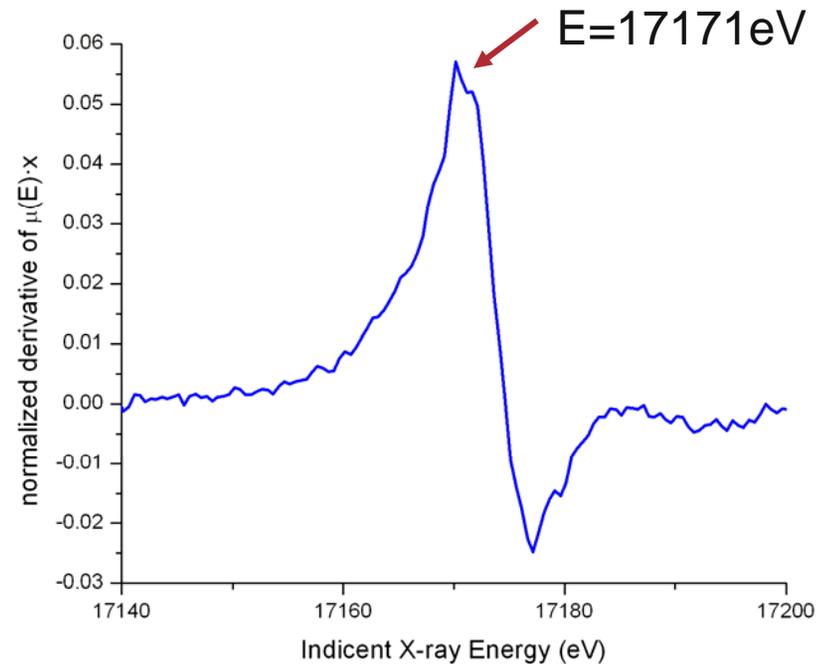
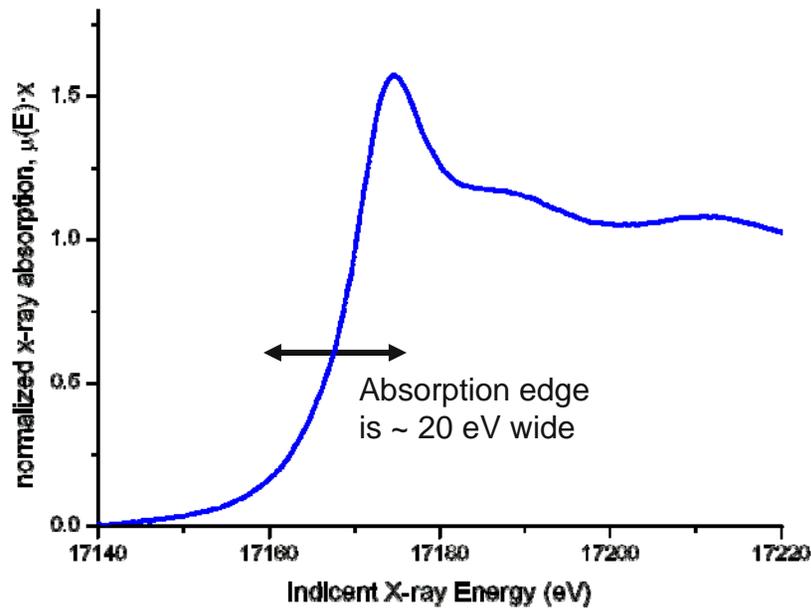


## Derivative of Reference Spectra Edge



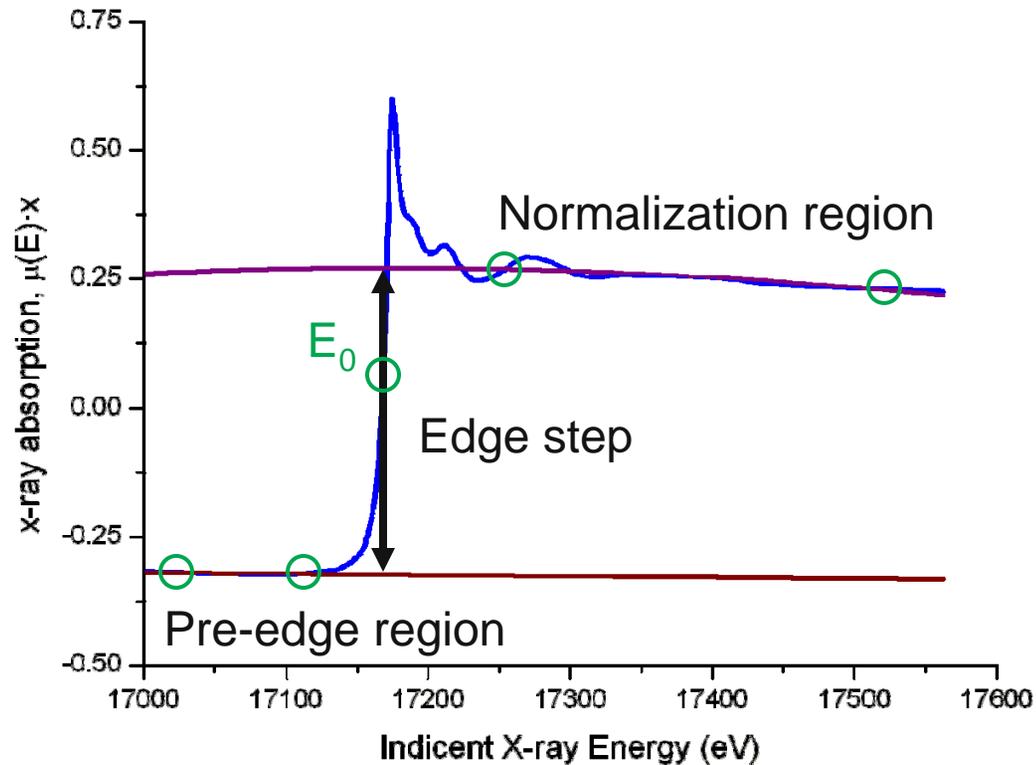
- Procedure
  - Reference spectrum 2 is aligned to reference spectrum 1 using derivative of edge
  - Data set 2 and reference 2 are shifted by the amount determined.
  - Data sets 1 and 2 are merged.
- It is good practice to align all the spectra to the same reference spectra for a given project.
- Data are often averaged as absorption spectra

## Edge Energy



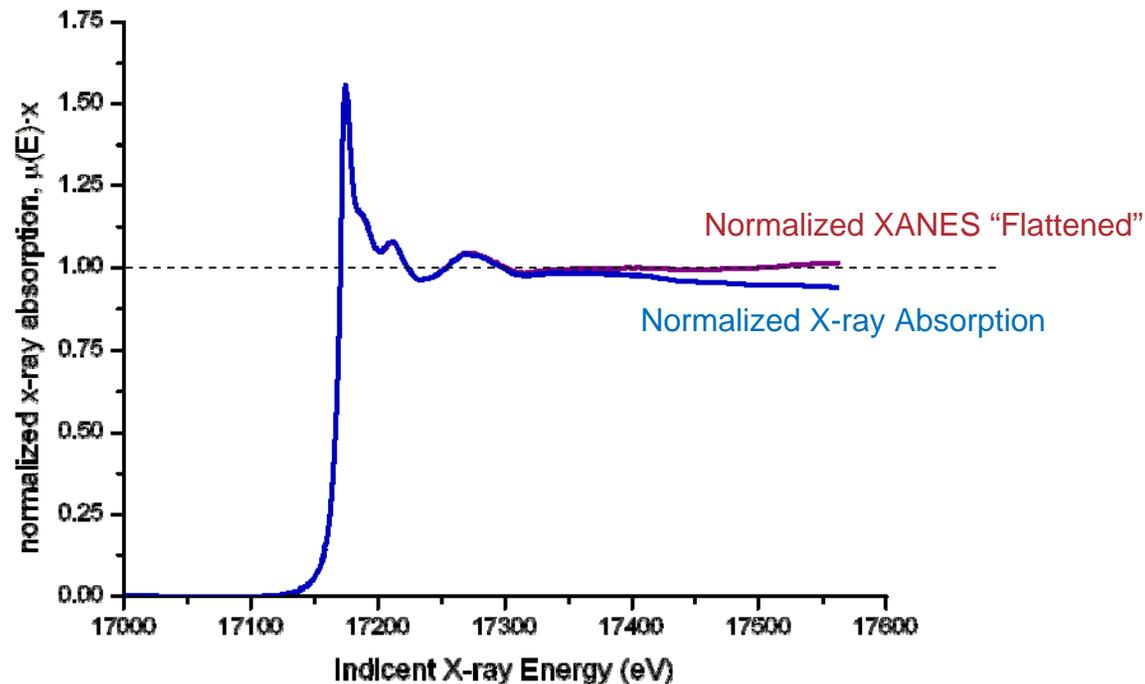
- The U  $L_{III}$ -edge absorption energy for U is defined as 17166 eV.
- The measured absorption edge is broad covering many eV.
- The first derivative of the edge for U(VI) is by convention set to 17171 eV and is useful for XANES comparisons.
- For EXAFS analysis  $E_0$  (the edge energy) is used to defined  $k = 0 \text{ \AA}^{-1}$  and is used to align the measured spectra to theoretical calculations.

## Normalized X-ray Absorption Spectra



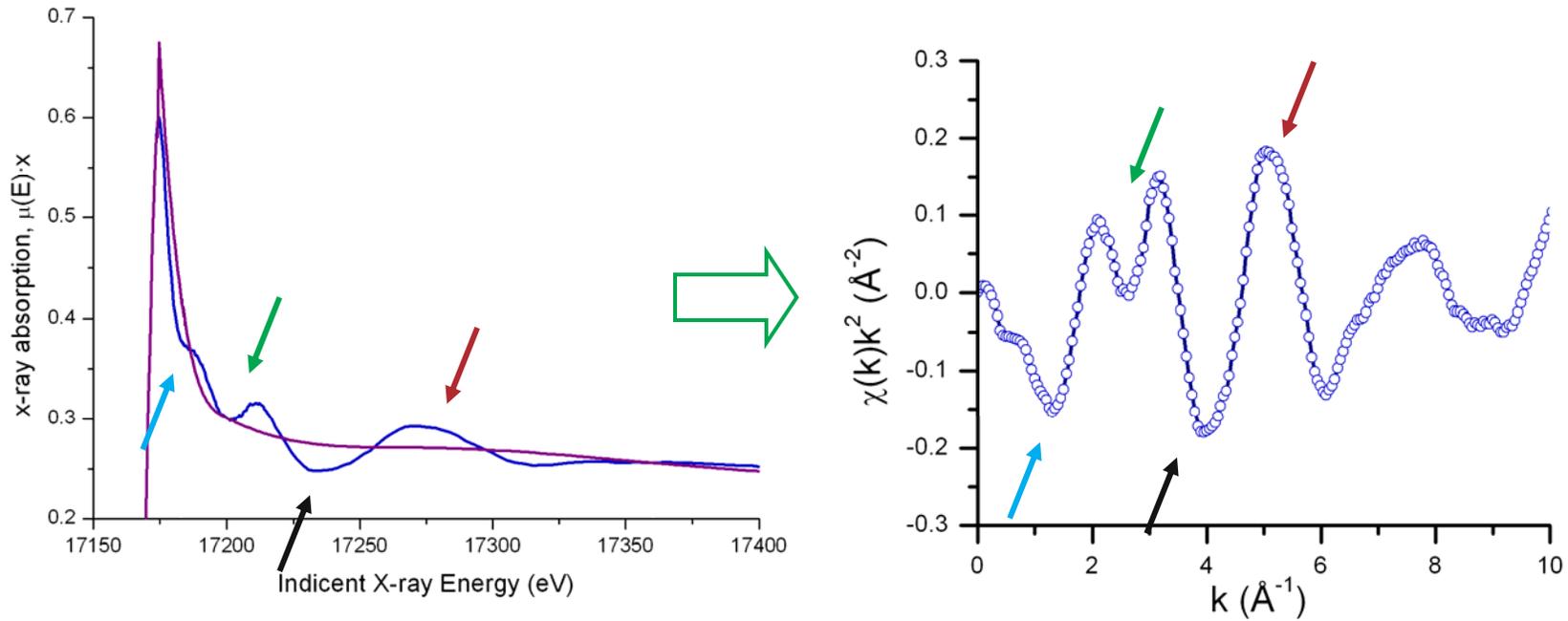
- Pre-edge line 200 to 50 eV before the edge
- Normalization line 100 to ~400 eV after the edge
- Edge step the change in the absorption coefficient at the edge
  - Evaluated by taking the difference of the pre-edge and normalization lines at  $E_0$

## Normalized X-ray Absorption Spectra



- Normalized X-ray Absorption Spectra is calculated by subtracting the pre-edge line from the entire spectra and dividing the entire spectra by the absorption edge step
- Athena has an extra feature used to flatten the absorption spectra above the edge, which can be helpful for comparing XANES spectra from different detectors.

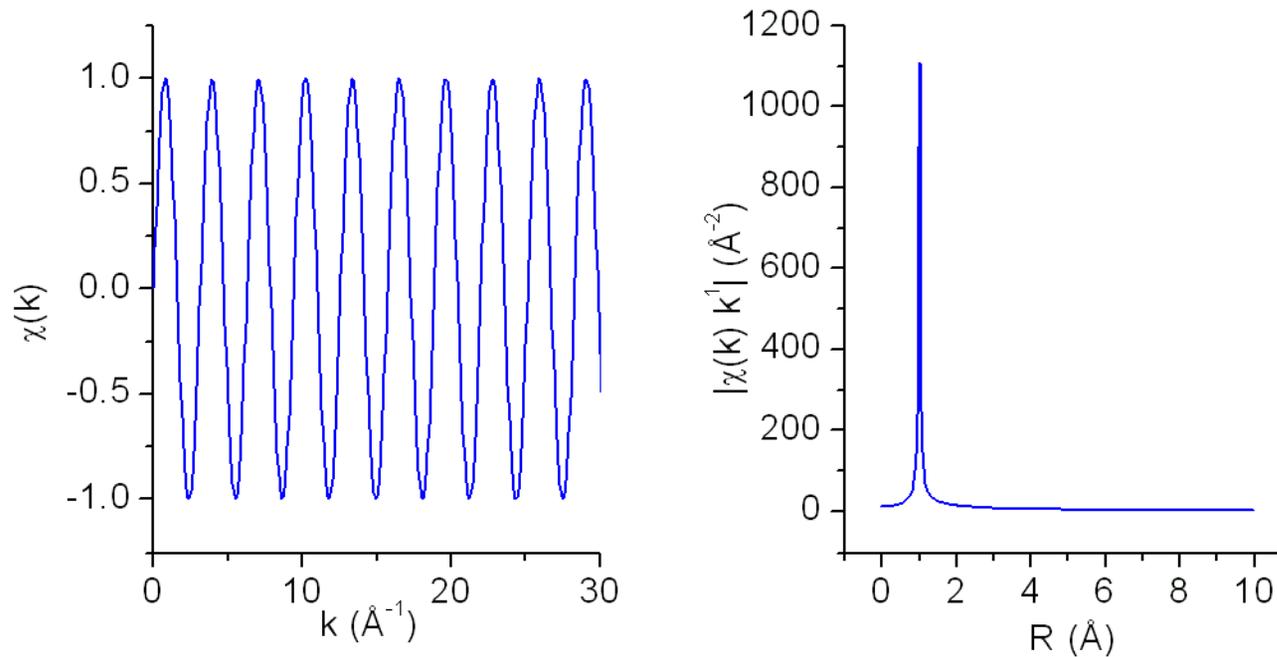
# Conversion from Energy to Wavenumber



$$k^2 = \frac{2m_e (E - E_0 + \Delta E_0)}{\hbar^2}$$

Mass of electron  $m_e$       Energy above edge  $E - E_0$       Energy shift to align data to theory  $\Delta E_0$   
 wavenumber  $k$       Planck's constant  $\hbar$

## Fourier Transforms

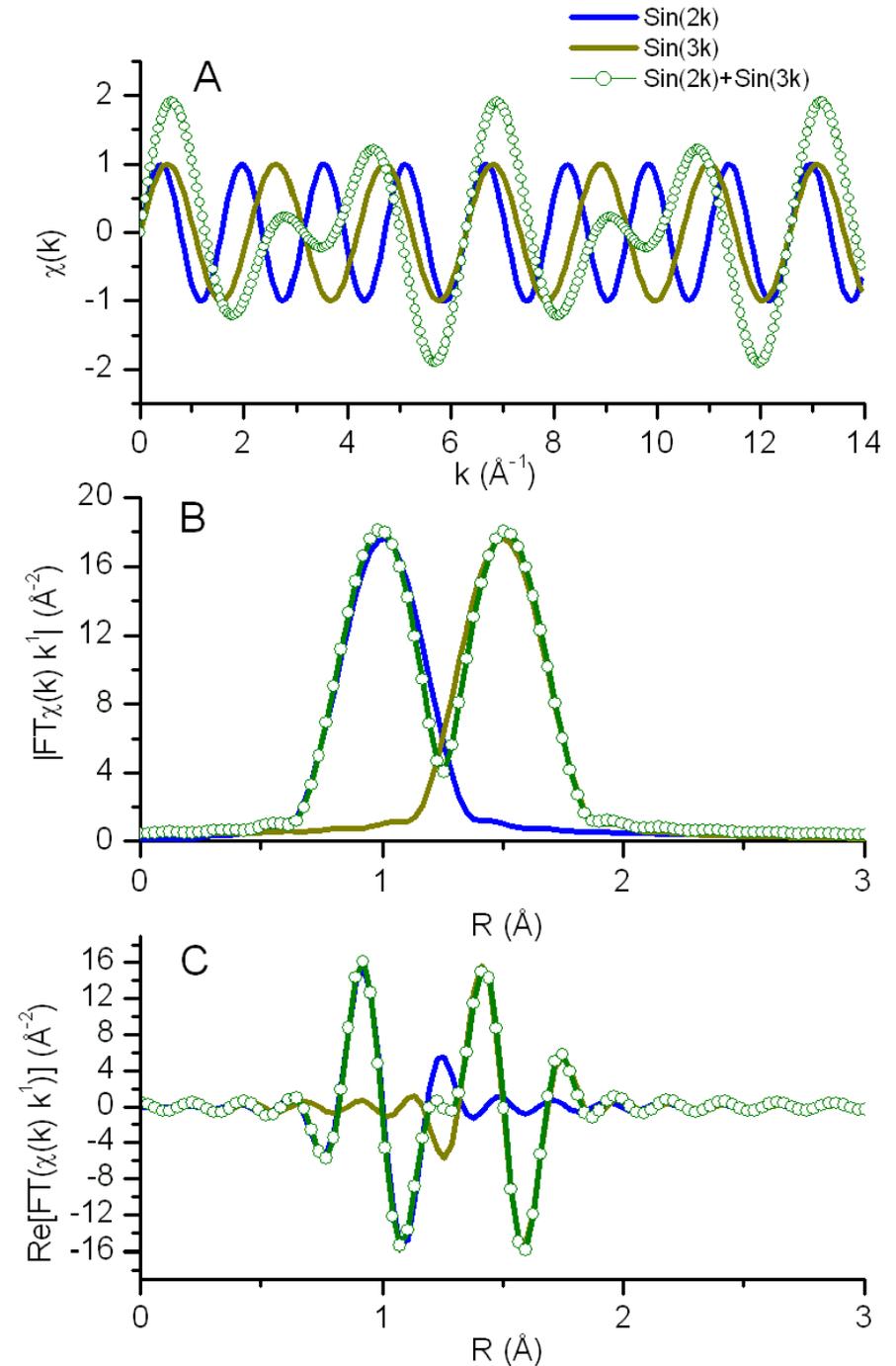


- Fourier transform of an infinite sine wave with a single phase of  $2k$  is a delta function at  $R = 1$   $\text{\AA}$ .
- Signal that is de-localized in  $k$ -space is localized in  $R$ -space
- FT is a frequency filter

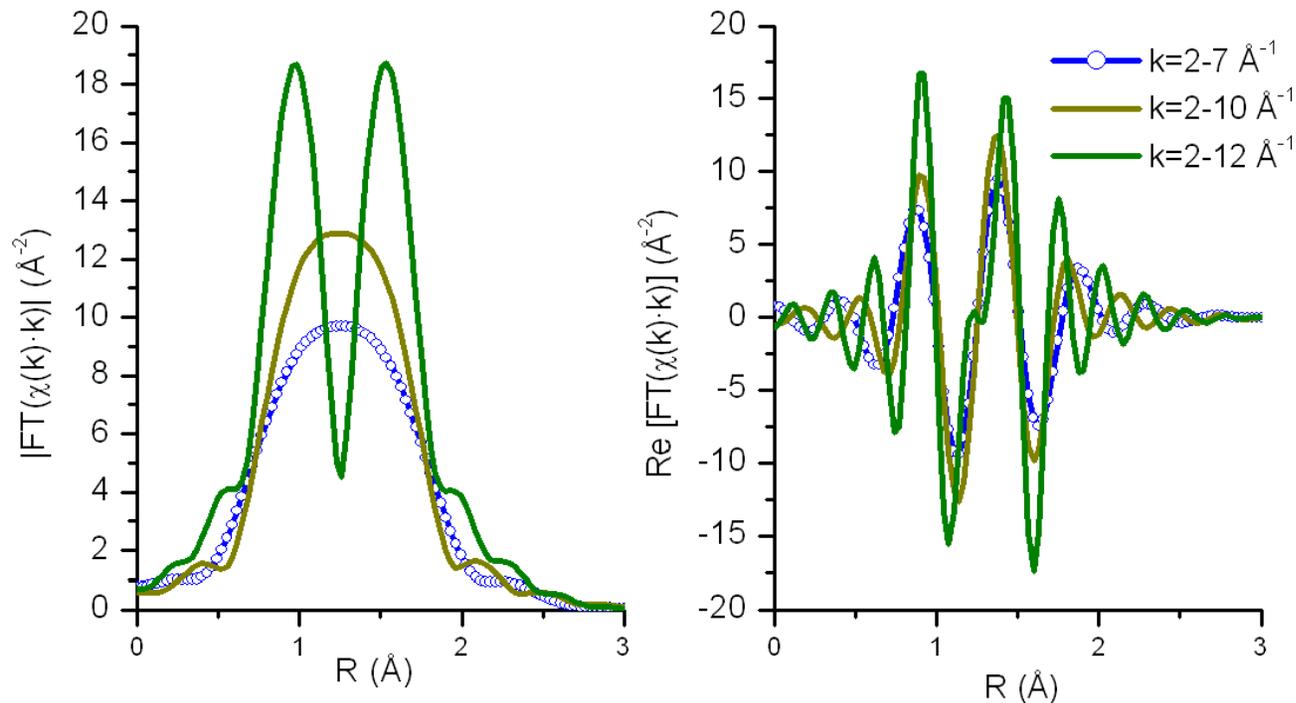
## FT of two phase sine wave

- The Fourier transform of finite data range is a broad peak rather than a delta function
- The real part of the FT is a sum of the components of the FT of each sine wave
- The information content of a FT signal is given by Nyquist theorem

$$N_{IP} = \frac{2}{\pi} \cdot \Delta k \cdot \Delta R + 1$$



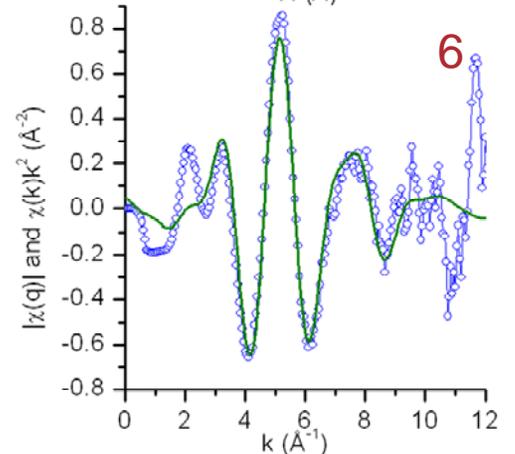
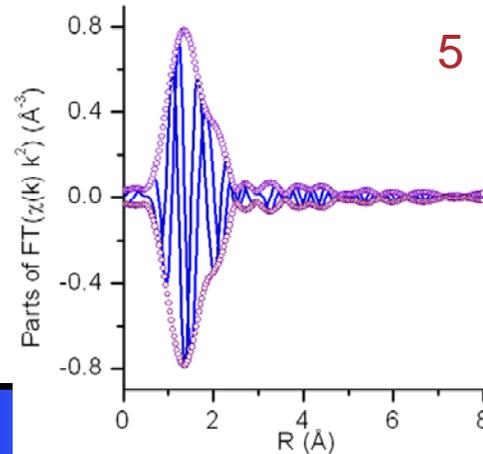
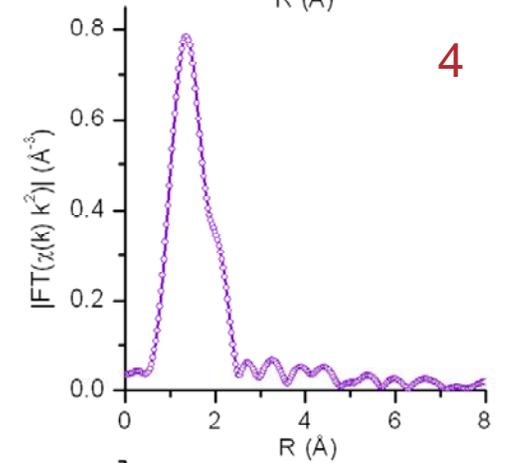
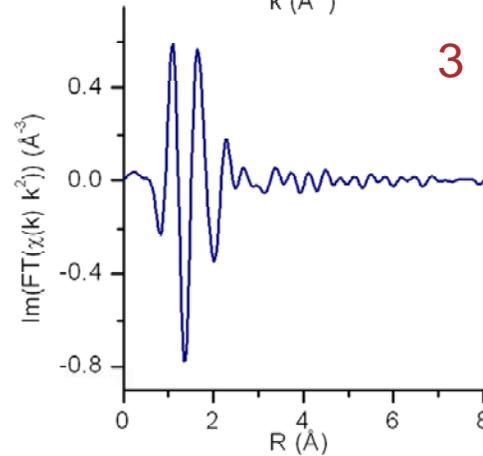
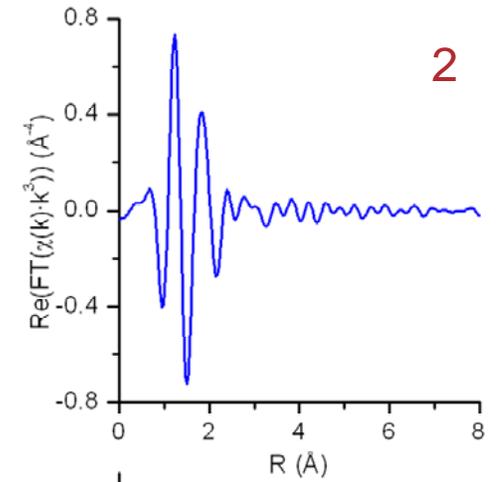
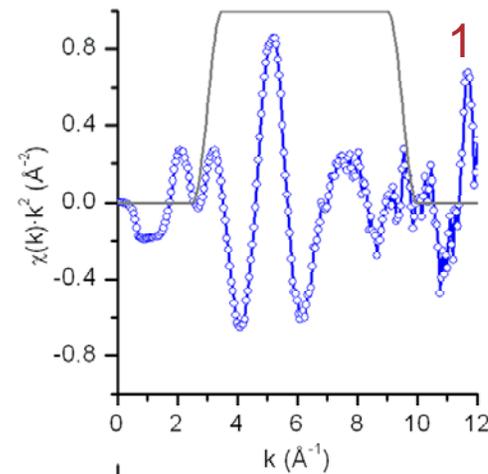
## Information Content in the Fourier Transform



- Increasing the k-range included in the Fourier transform increases the information contained in the Fourier transformed signal
- All signals are included in the FT from  $k=0$  and their content is carried to the FT signal
- The resolution given in these signals is  $R = 0.3 \text{ \AA}$ ,  $0.2 \text{ \AA}$ , and  $0.15 \text{ \AA}$ , hence the signal separated by  $1 \text{ \AA}$  can be resolved even with the lowest k-range

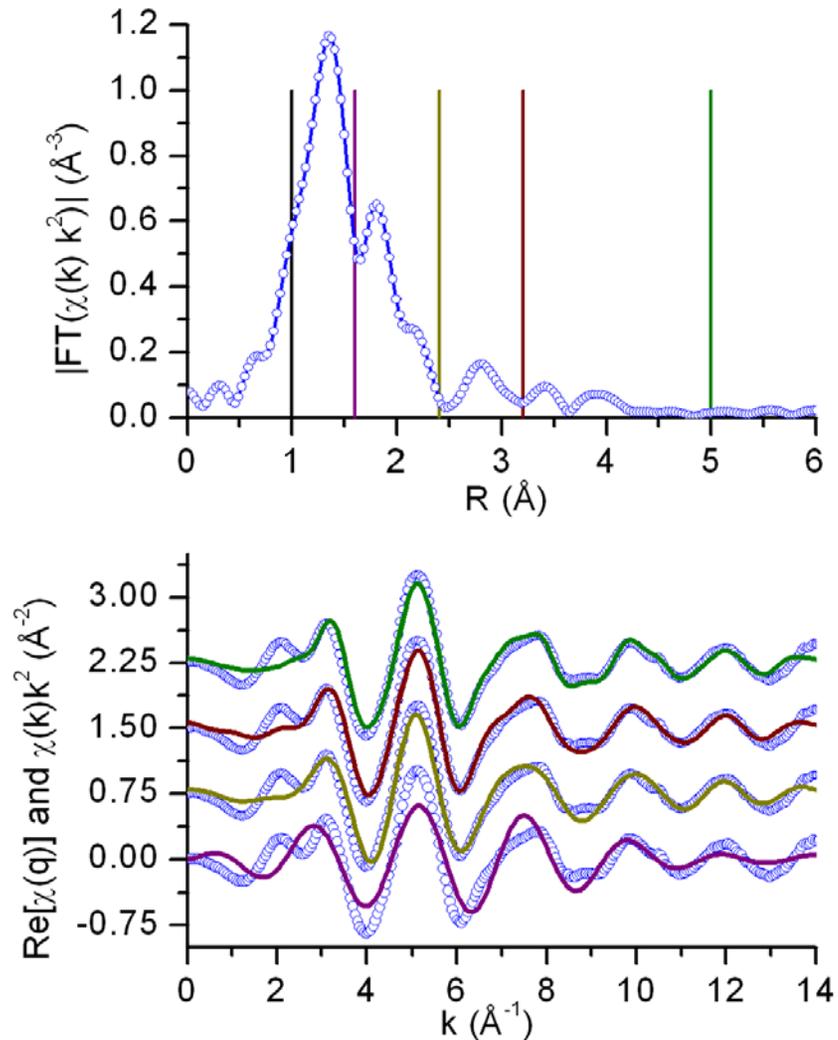
# Parts of Fourier Transform

- 1: EXAFS spectra and window function
  - 2: Real part of FT
  - 3: Imaginary part of FT
  - 4: Magnitude of FT
  - 5: Real, imaginary, magnitude and inverse of magnitude of FT
  - 6: EXAFS spectra and back Fourier transformed spectra
- The real and imaginary parts of the Fourier transform contain more information than the magnitude of the FT.



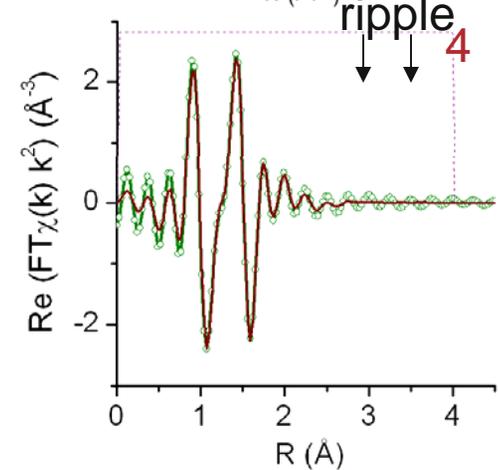
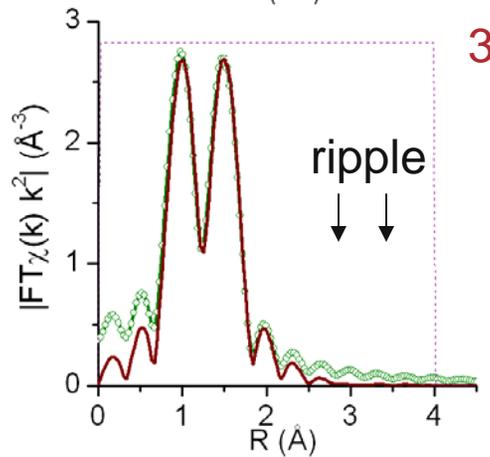
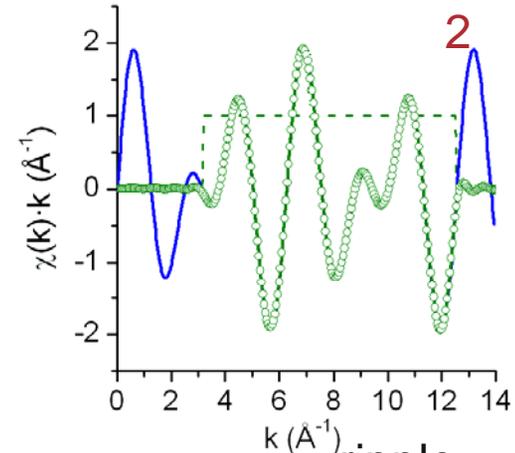
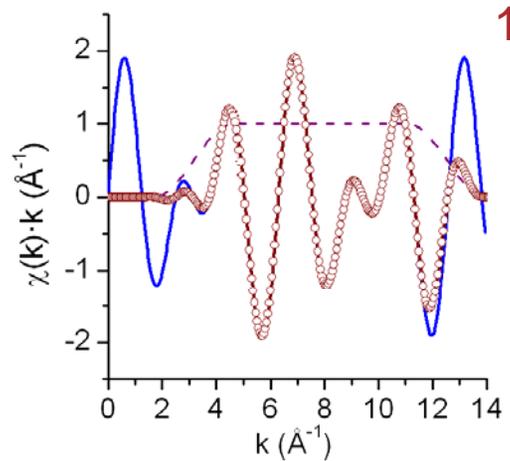
## Back Fourier Transform

- The Back Fourier transform contains the information within the R-range.
- Used to compare the signal content within an R-range to the original EXAFS signal
- Longer phase signals are Fourier transformed to peaks at lower R values



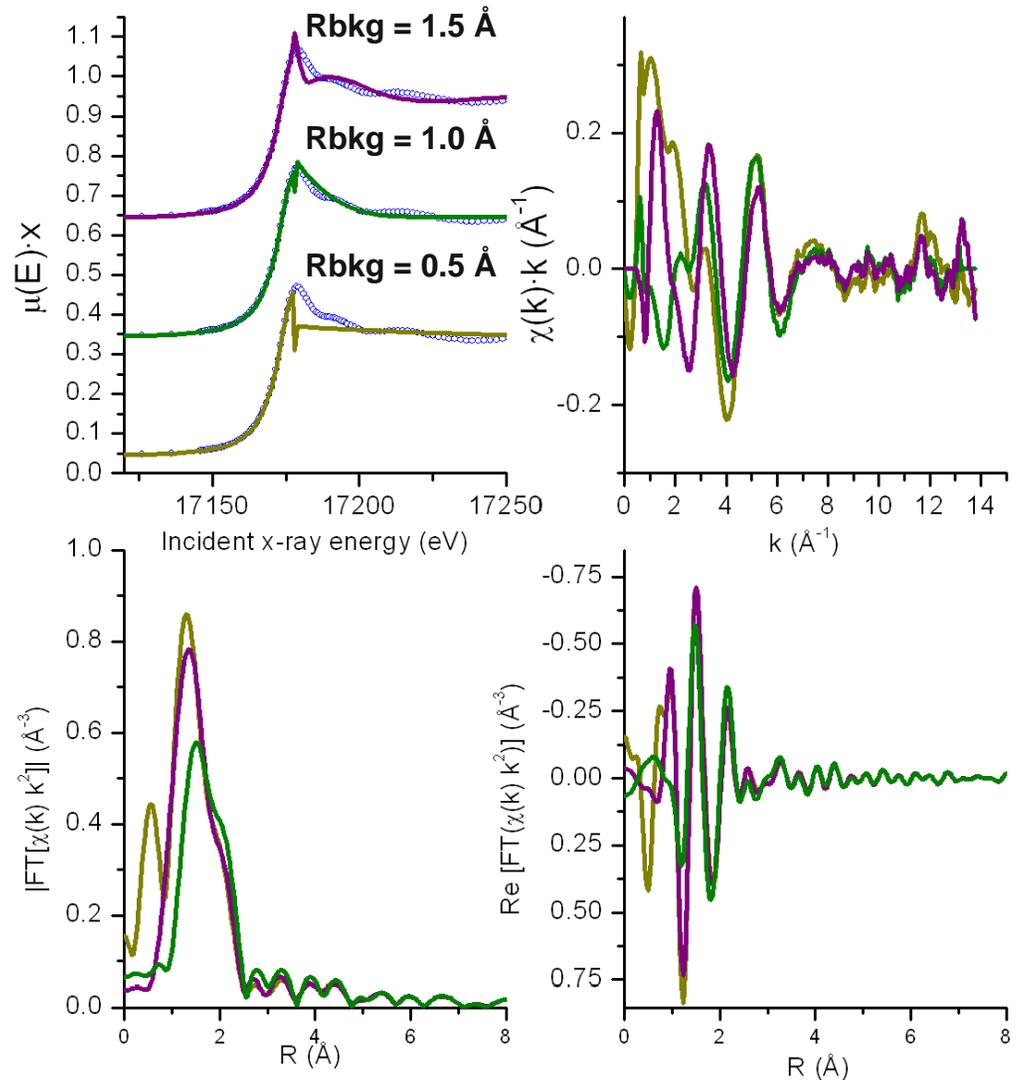
# Fourier Transform Ripple

- Same data in blue is shown in 1 and 2.
- FT window is **broad** in 1 and **sharp** in 2
- Magnitude and real part of FT is shown in 3 and 4.
- Sharp window results in a FT ripple
- Back Fourier transformed spectra are shown in 1 and 2 illustrating the abrupt change in the green spectrum

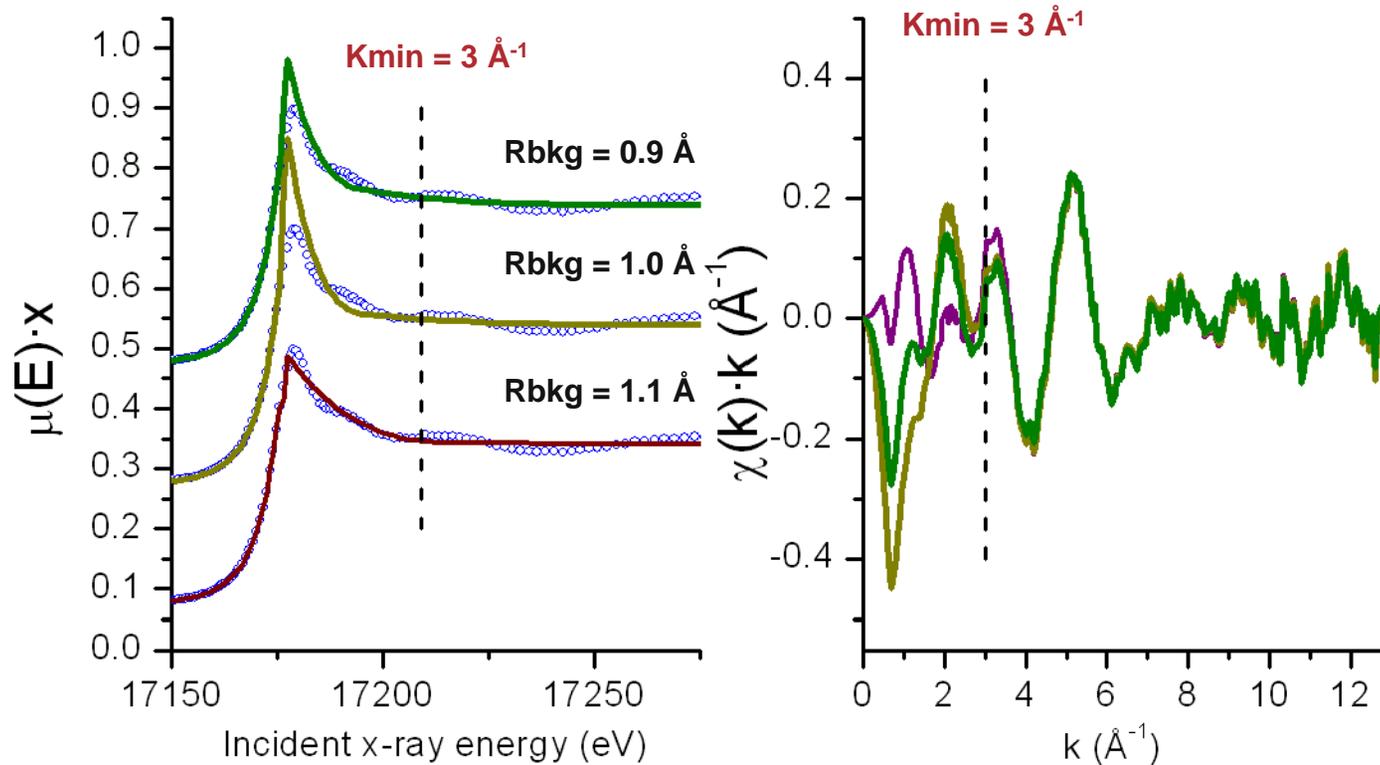


## Effect of a large change in Rbkg

- Rbkg: Controls the curvature of the background and is usually set to about half the first nearest neighbor distance.
- Small values for Rbkg (0.5 Å) result in significant signal at low R values, where no neighboring atoms are present.
- Large values for Rbkg (1.5 Å) result in the removal of signal from the first shell signal.



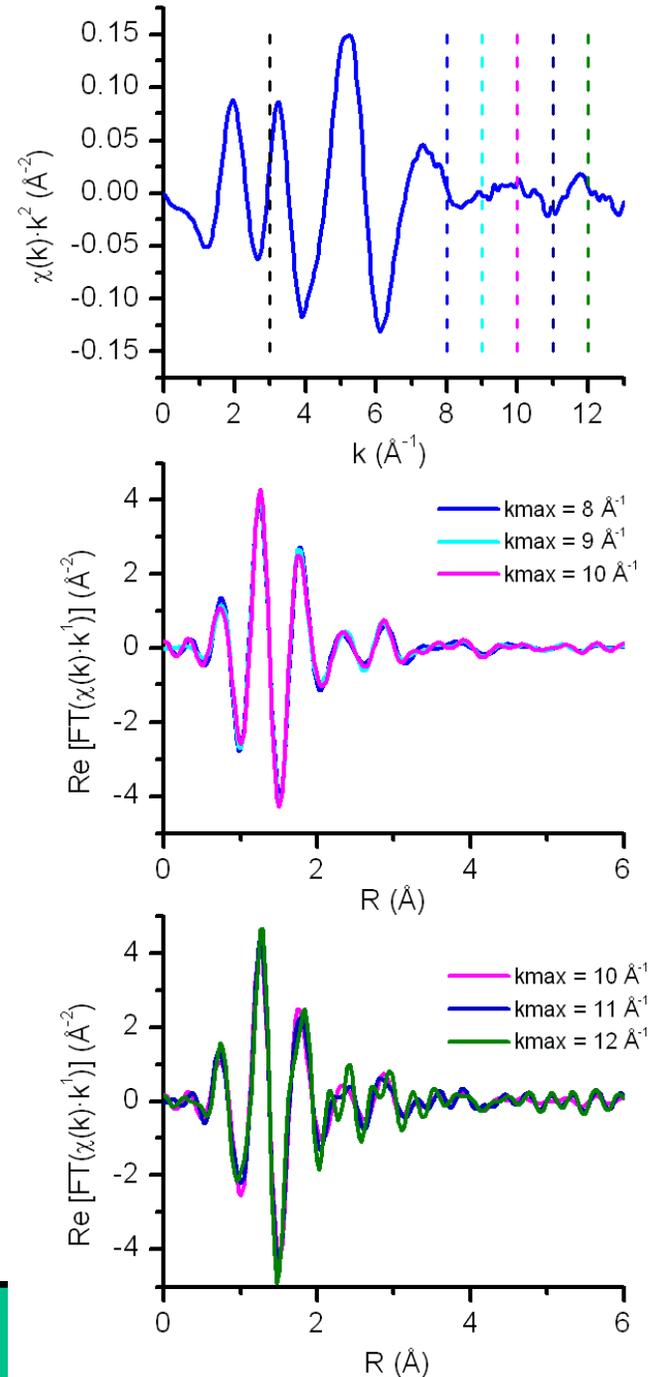
## Effect of a small change in Rbkg



- Small changes in Rbkg can be used to determine the minimum k-range to use in the Fourier transform.
- EXAFS signal should not depend on Rbkg.
- $K_{min}$  of  $3 \text{ \AA}^{-1}$  uses the part of the spectra that does not depend on Rbkg.

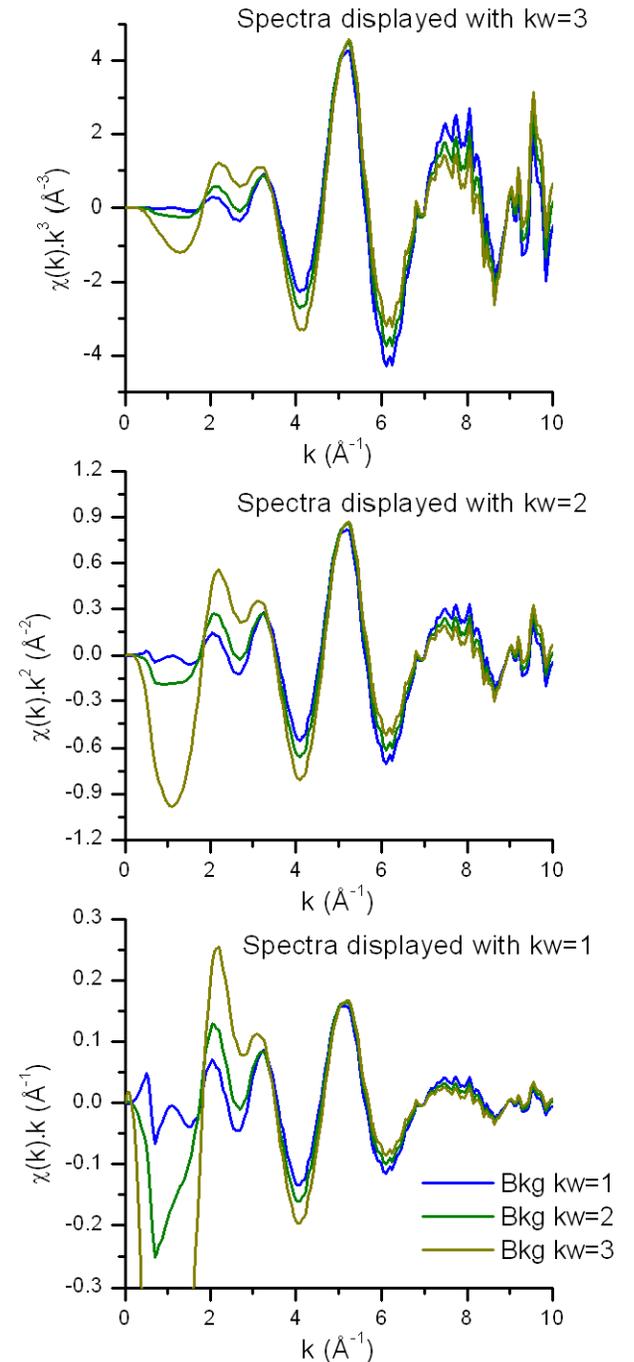
# Choosing $K_{max}$ in the Fourier Transform

- Comparison of the Real part of the Fourier transform using incremental values for the maximum k-value ( $K_{max}$ ) can be used to determine  $K_{max}$ .
- The Real part of the Fourier transform will be smooth and similar for the different  $k_{max}$  values as long as significant noise is not included in the Fourier transform.
- $K_{max}$  values of  $11 \text{ \AA}^{-1}$  and  $12 \text{ \AA}^{-1}$  include some noise in the FT



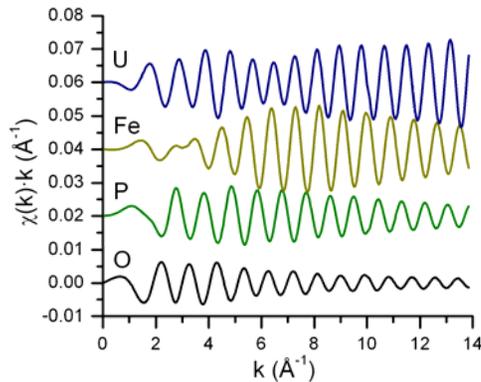
## Effect of k-weight in the background removal process

- Background is removed by using a k-weight of 1, 2, or 3.
- Resulting EXAFS signal is displayed using a k-weight of 1, 2, or 3
- Use the background k-weight that results in an evenly weighted EXAFS signal at low k, independent of the k-weight used to display the spectrum

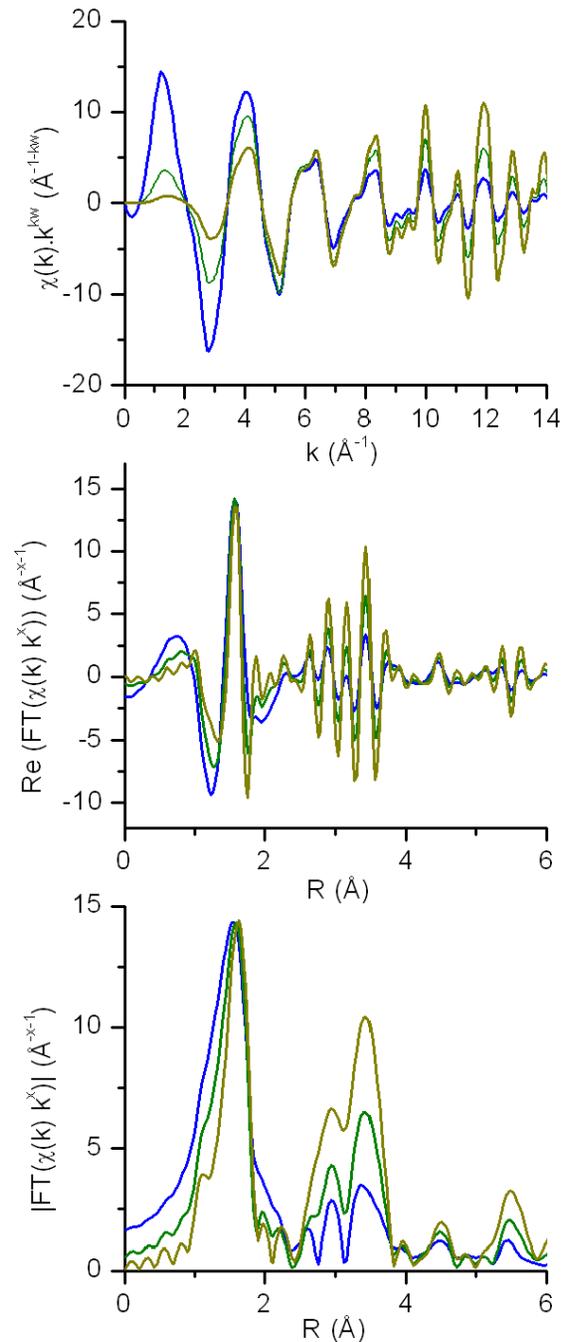


## K-weight used in Fourier Transform

EXAFS signal for U-X neighbor at 4 Angstroms



- EXAFS signal is processed with k-weight of 1, 2, and 3 and then rescaled so that the signal is the same height for the first shell in the Fourier transform.
- The signal from 3 to 4  $\text{\AA}$  increases with k-weight indicating that there is a atom with stronger signal at higher k-values in this shell
- K-dependence of the EXAFS signal can be used to differentiate neighboring atom types and reduce correlations between EXAFS parameters



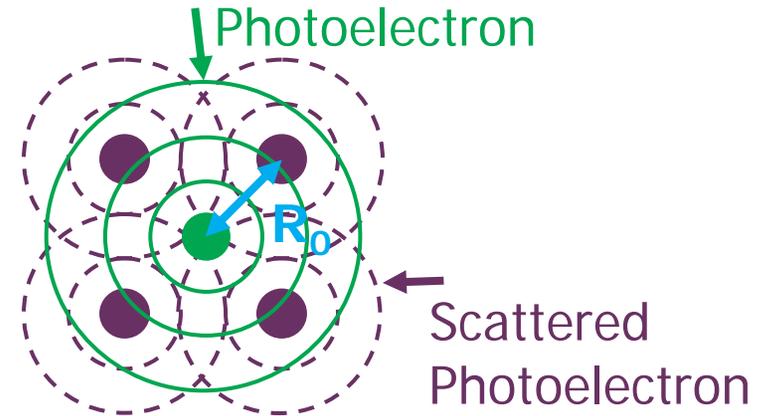
## EXAFS Equation

$$\chi(k) = \sum_i \chi_i(k)$$

$$\chi_i(k) \equiv \frac{(N_i S_0^2) F_{eff_i}(k)}{k R_i^2} \sin(2kR_i + \varphi_i(k)) e^{-2\sigma_i^2 k^2} e^{-\frac{2R_i}{\lambda(k)}}$$

$$R_i = R_{0i} + \Delta R_i$$

$$k^2 = \frac{2m_e(E - E_0 + \Delta E_0)}{\hbar}$$



### Theoretically calculated values

- $F_i(k)$  effective scattering amplitude
- $\varphi_i(k)$  effective scattering phase shift
- $\lambda(k)$  mean free path

### Starting values

- $R_0$  initial path length

### Parameters often determined from a fit to data

- $N_i$  degeneracy of path
- $S_0^2$  passive electron reduction factor
- $\sigma_i^2$  mean squared displacement
- $\Delta E_0$  energy shift
- $\Delta R$  change in half-path length